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1 of 2 ORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO.: SERIAL NO.: (REV. 7-80) PATENT AND TRADEMARK OFFICE 57941.000041 09/976,170 INVENTOR'S NAME: EXAMINER: John P. Trimming IPE Jared ZERBE et al. LIST OF MATERIALS CITED BY APPLICANT FILING DATE: GROUP: October 12, 2001 2133 (Use several sheets if necessary) MAY 2 0 2004 **U.S. PATENT DOCUMENTS** SUBCL/SS EXAMINER DOCUMENT NUMBER DATE NAME CLASS 3869580 03-04-1975 1. Ragsdale MAY 2.4 200 3909563 09-30-1975 2. Ghosh et al. Techhology Center 2100 3. 4271514 06-02-1981 Parras et al. 4727540 02-23-1988 4. Lacroix et al. 5. 5142495 08-25-1992 Canepa 5197062 03-23-1993 6. Picklesimer 7. 5228042 07-13-1993 Gauthier et al. Zerbe 8. 5258986 11-02-1993 9. 5265089 11-23-1993 Yonehara 10. 5383177 01-17-1995 Tateishi 5392298 02-21-1995 11. Shinjo 12. 5412665 05-02-1995 Gruodis et al. 5430736 07-04-1995 13. Takeoka et al. 5444715 14. 08-22-1995 Gruetzner et al. 5473619 12-05-1995 Sakaguchi 15. 5485473 01-16-1996 Diebold et al. 16. 5490150 02-06-1996 17. Andrews et al. Elpers et al. 18. 5519719 05-21-1996 19. 5675588 10-07-1997 Maruyama et al. 20. 5790523 08-04-1998 Ritchie, Jr. et al. 21. 5831996 11-03-1998 Abramovici et al. 22. 5841271 11-24-1998 Nakayama 23. 5875177 02-23-1999 Uriu et al. 24. 5938784 08-17-1999 Kim 25. 5999022 12-07-1999 Iwata et al. 26. 6061817 05-09-2000 Jones et al. 27. 6073263 06-06-2000 Arkin et al. 28. 6160790 12-12-2000 Bremer 6201829 29. 03-13-2001 Schneider

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